

## 2nd probe card

Wafer ID: 03B6, 06H2, 04B1

Start date: 2024-06-24

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There were 317 total error messages and 158 actual errors in 3 wafer(s). 56 were repeats and will not be shown below.

Number of scan chain errors: 16

Number of analog scan failures: 3

Number of digital scan failures: 15

Number of VDD errors: 4

Number of chips with dead pixels: 17

Number of DAQ function program terminations: 0

Number of programming errors: 0

Number of DAQ digital scan errors: 15

Number of DAC calibration errors: 12

Number of temperature measurement errors: 0

Number of LDO measurement errors: 2

Number of IREF trimming failures: 6

Number of threshold scan failures: 0

Number of overvoltage trip errors: 1

Number of data merging errors: 0

51 chip(s) did not complete testing.

Total number of dead pixels: 100 (of 435456 in 3 wafer(s))

Other errors (6):

- Testing of global registers failed!
- Caught exception from registers test!
- No data from registers test!
- Measured values in SLDO mode not within tolerance!
- DAQ function global\_registers\_test terminated unexpectedly!
- The test could not be completed!

